



# Dislocation patterns in Cu-OFE by EBSD and their relation with BD

Advanced studies

Enrique RODRIGUEZ CASTRO  
(CERN & University of Vigo)

# Outline

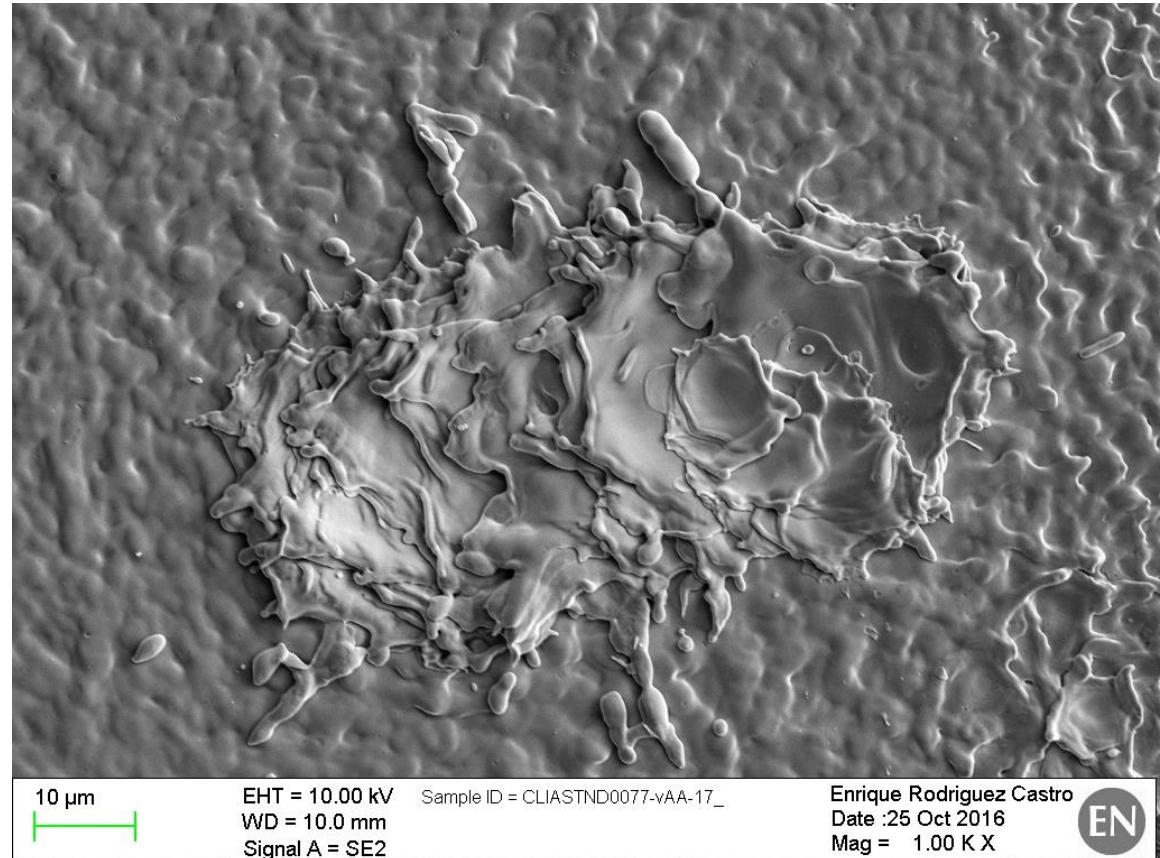
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	Aim of the study	
Protocol	Sampling	Heat treatment
		Tensile test
		Fatigue Test
	Characterization method	EBSD (KAM)
Results	Tensile test	
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		Reference
		Fatigue 83% LT
		Fatigue 100% LT
		Summary of results
	15 µm stepsize	Reference
		Fatigue 65% LT
		Summary of results
Perspective		
Conclusions		

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Conclusions		Enrique Rodriguez Castro		

# Context:

- CLIC have especial interested in understanding BD phenomena
- BDs develop in isolated or clusters of craters in the surface of CLIC-AS
- Dislocations seem to play an important role in the BD phenomena
- Find a non-destructive diagnostic technique which determines dislocation presence, density and patterns.

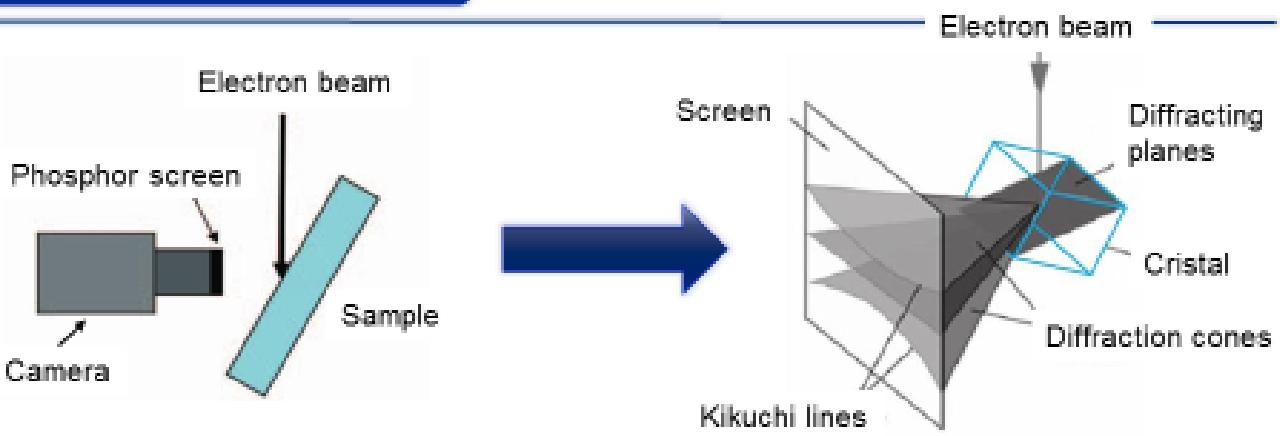


# Aim of the study

- Two objectives:

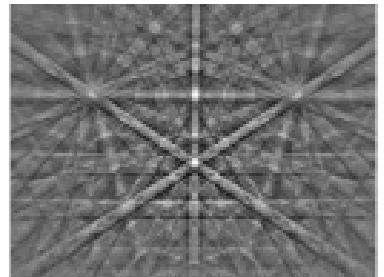
1. Establishing EBSD as a valid diagnostic ***non destructive*** technique which determines the presence of dislocations and/or density in Cu-OFE used in CLIC-AS
2. Study dislocations role in the locations of FE/BD sites

## 2. Dislocation structures



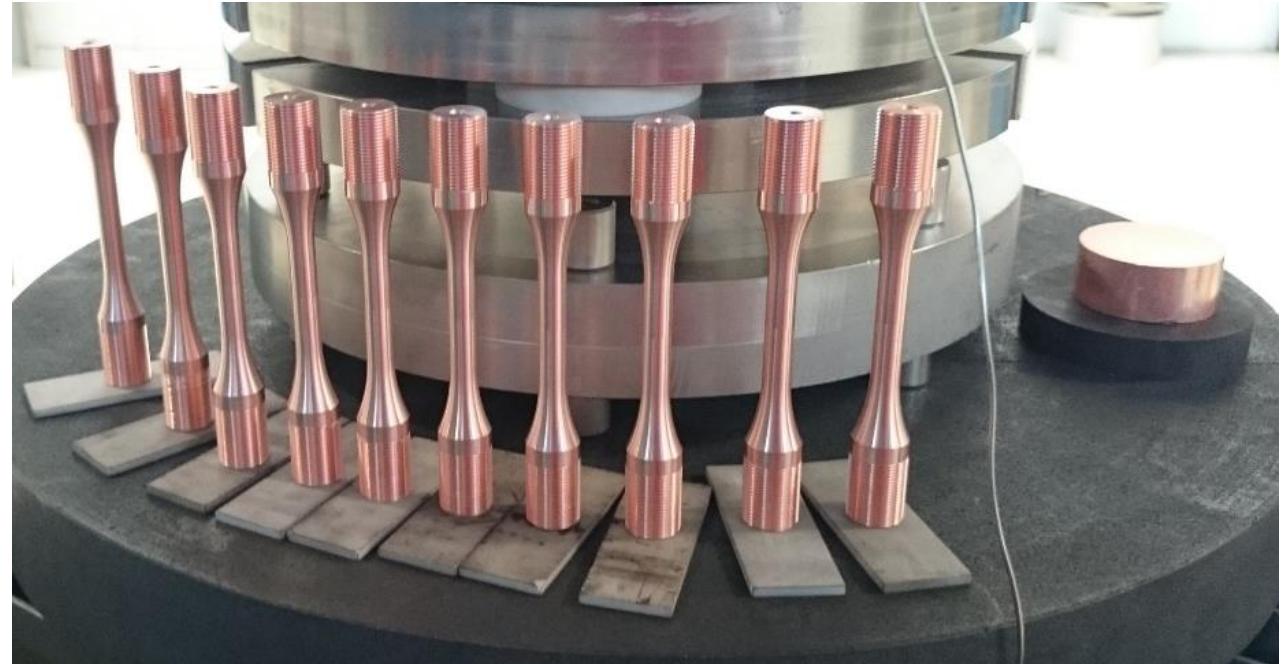
Ref:[BAU10]

- ✓ Diffraction of back scattered electrons
- ✓ Following Bragg condition
- ✓ Diffraction cones
- ✓ Kikuchi lines
- ✓ Diffraction pattern



# Aim of the study:

- To study the relation
  - Sample free of dislocation, or as few as possible
  - Sample with dislocations
- To introduce dislocation
  - Tensile test
  - Fatigue test
- To study and quantify the dislocations
  - Non destructive way
  - Large area
  - EBSD
- To have sample “free of dislocation” → heat treatment

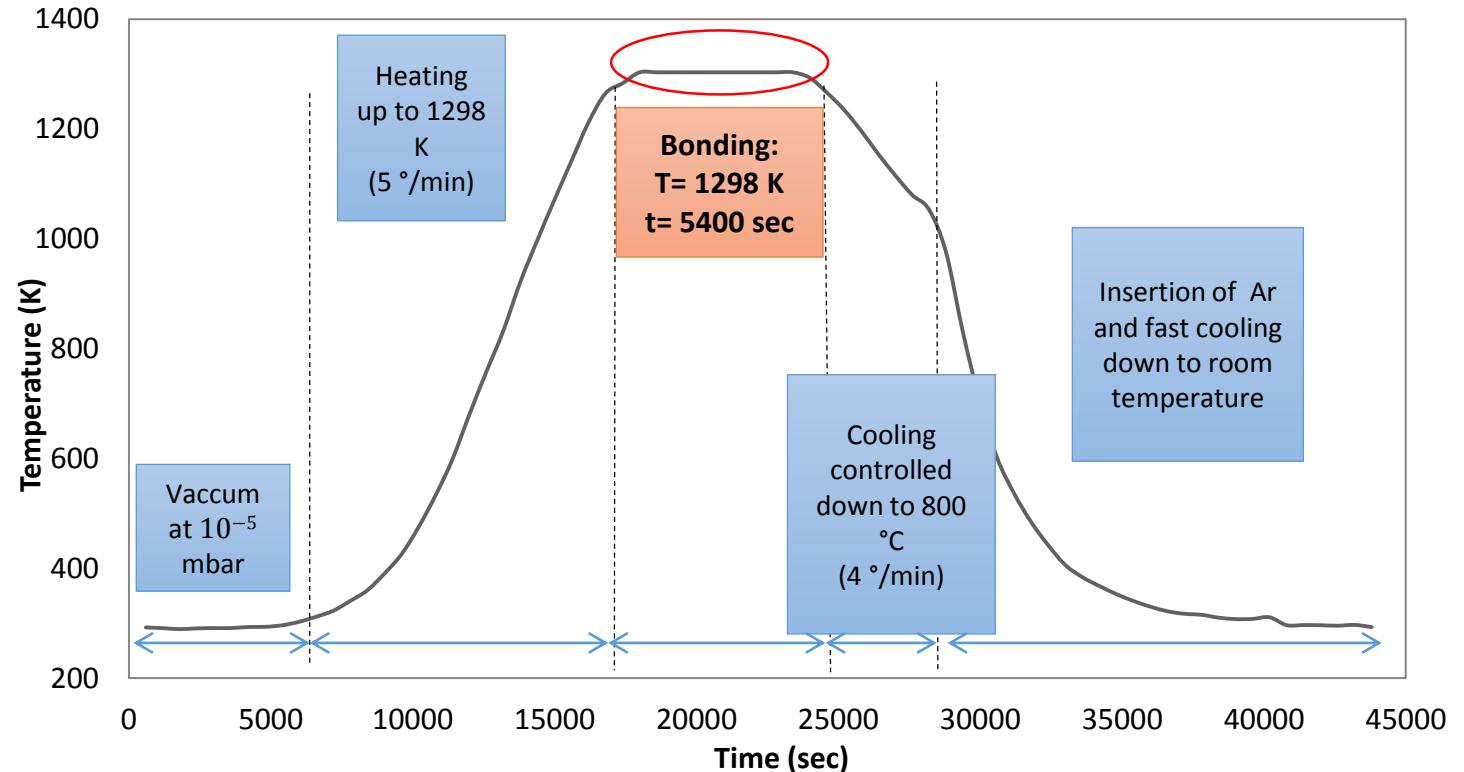


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<b>Conclusions</b>			

# History of samples and sample preparation

- Tensile and fatigued specimens
  - Same Cu-OFE CLIC-AS
  - Heat treated:
    - Same heating cycle as real structures
    - No H<sub>2</sub>
    - But Ar for cooling



# Fatigue and Tensile tests

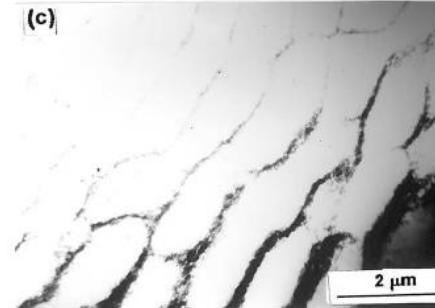
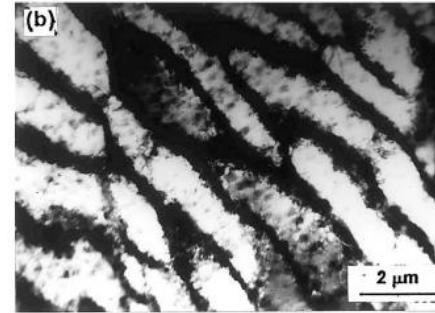
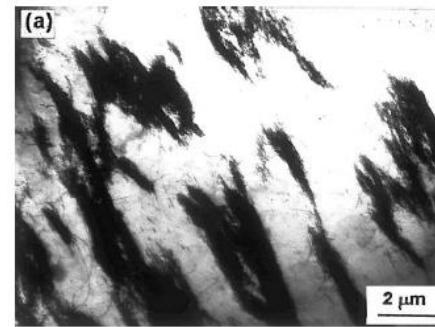
- Fatigue

- Pros:
  - Creation of dislocation structure (ladder type)
- Cons:
  - Not possible to do it in house at CERN
  - Difficulties to determine the stress and number of cycles (stress control mode)

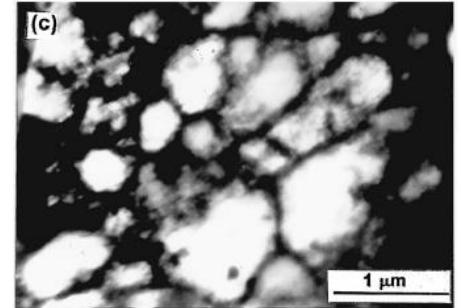
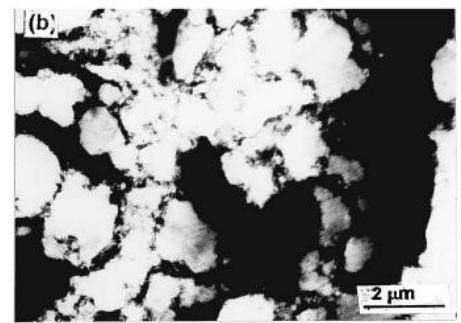
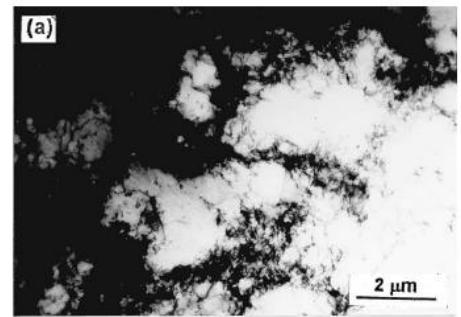
- Tensile

- Pros:
  - Easy repeatability
  - Equipment in house
  - Creation of dislocation structures (cell type)
- Cons:
  - EBSD not successful... yet

Fatigue



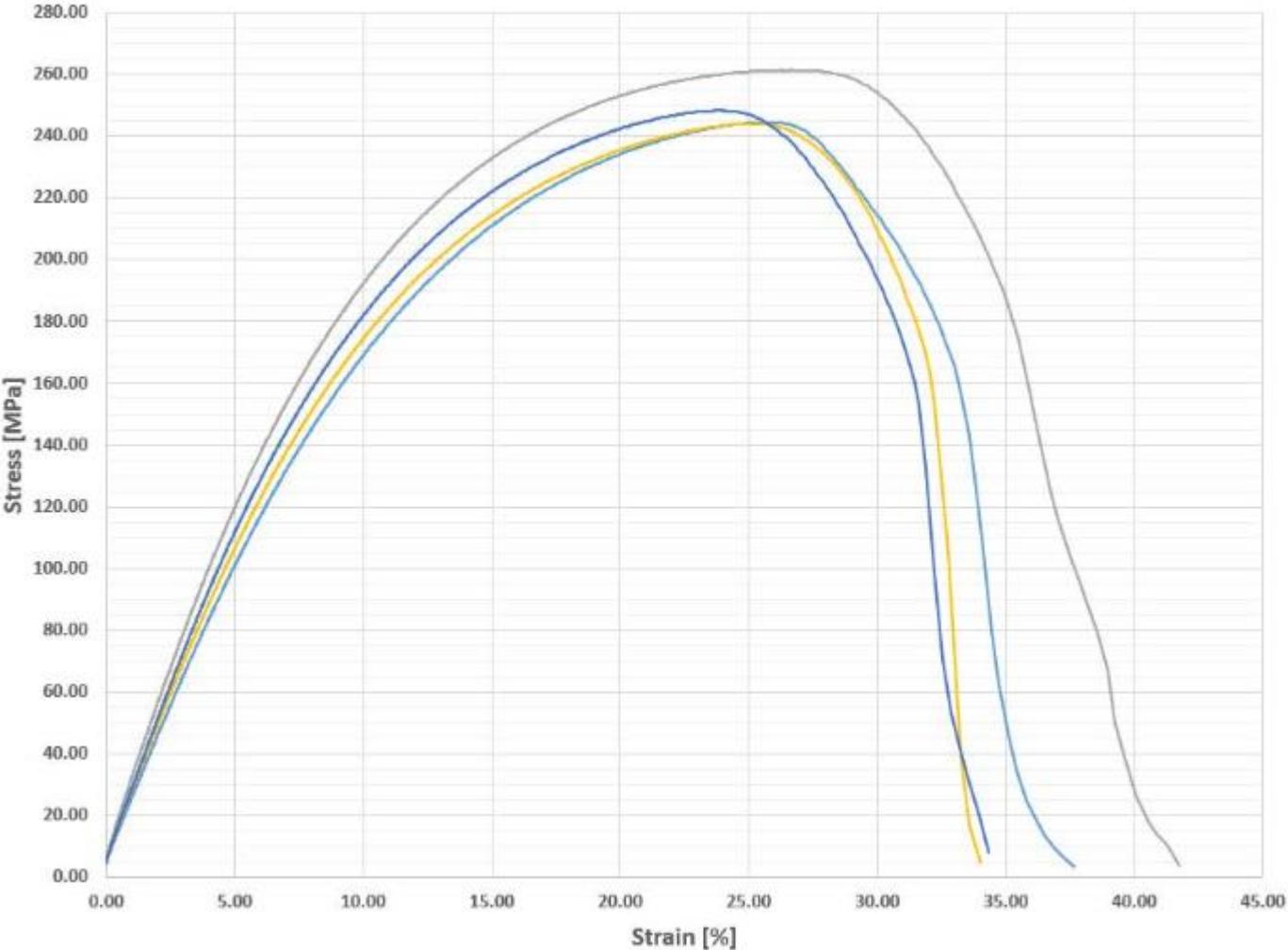
Tensile



TEM image of Cu samples (Mechanical behavior and the evolution of the dislocation structure of copper polycrystal deformed under fatigue-tension and tension fatigue sequential strain paths – W.P. Jia, J.V. Fernandes)

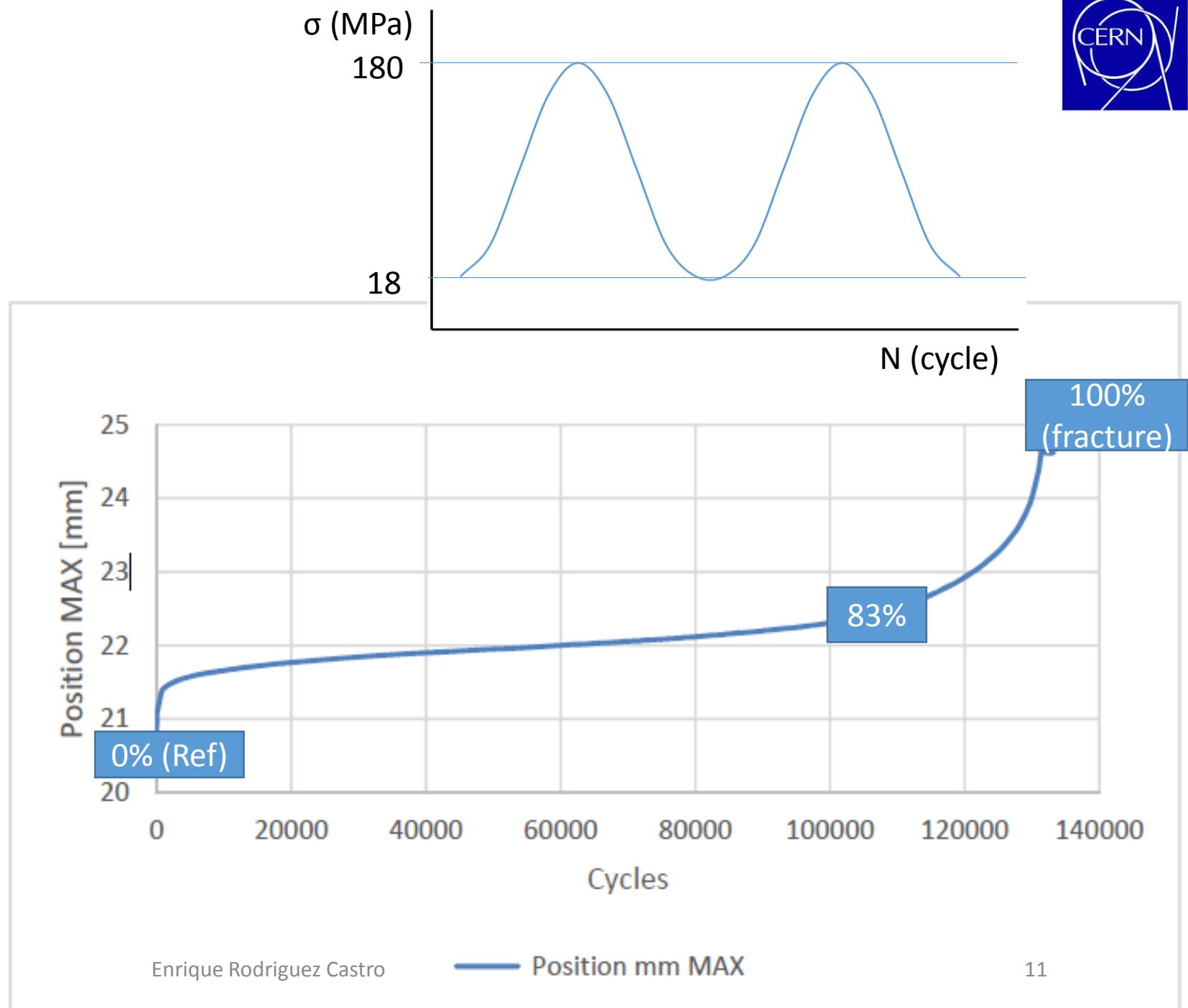
# Tensile test

- Fracture
- 35% strain
- 30% strain
- 20% strain
- 0% → reference

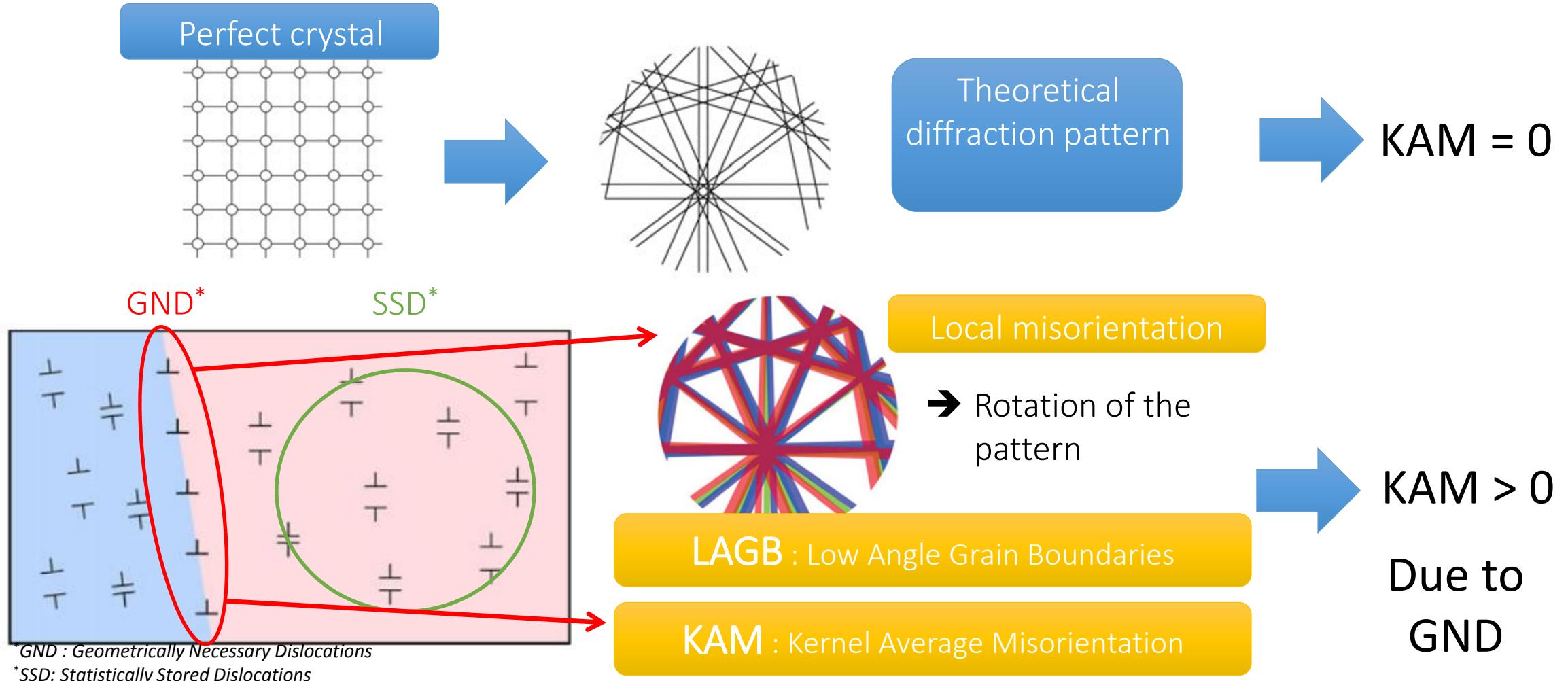


# Fatigue test

- $R=0.1$
- $\sigma_{\text{Max}}=180 \text{ MPa}$
- Fracture: 100% of life time = 131700 cycles
- 83% of life time = 109700 cycles
- Reference: 0% of life time = 0 cycles

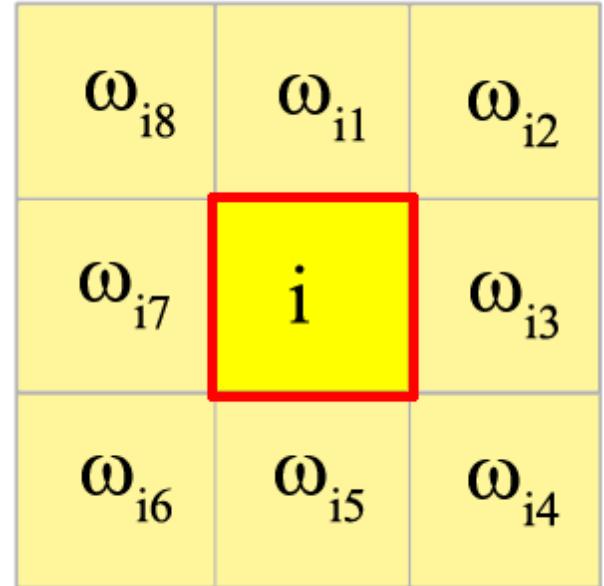


# Mis-orientation and dislocation



# EBSD study - KAM

- Kernel Average Mis-orientation
  - Can be used as a measure of local grain mis-orientation
  - Generally, higher in grains with higher dislocation density
- Compare every point with neighbor points
  - Assigns a value
  - 3x3 size
  - Comparison:
    - Mis-orientation maps (colour scale)
    - Histogram
- Two different step size
  - 0.2  $\mu\text{m}$
  - 15  $\mu\text{m}$

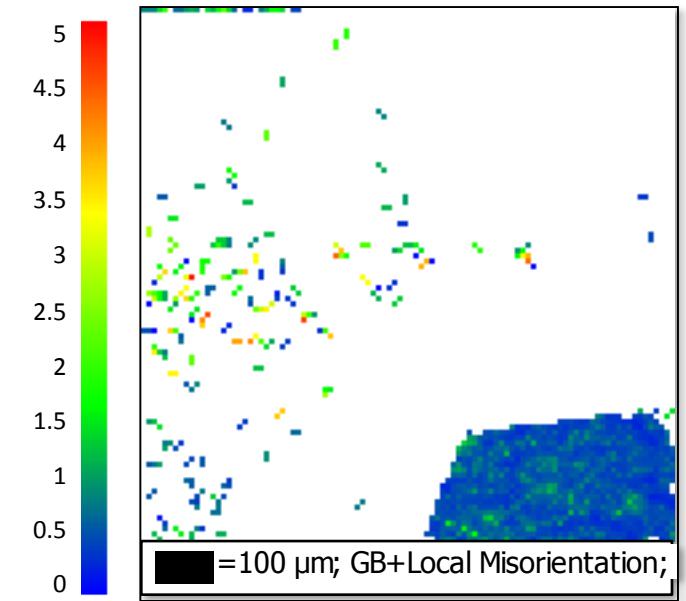
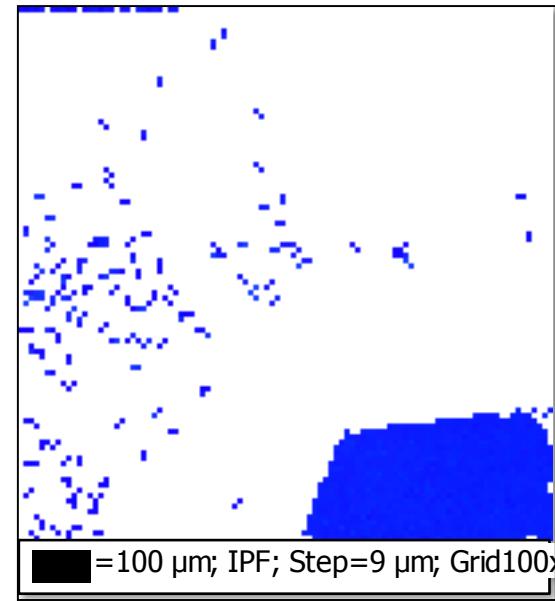
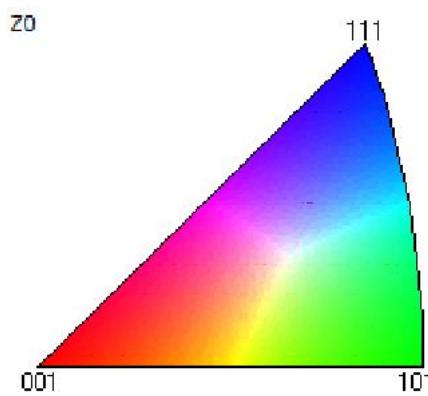
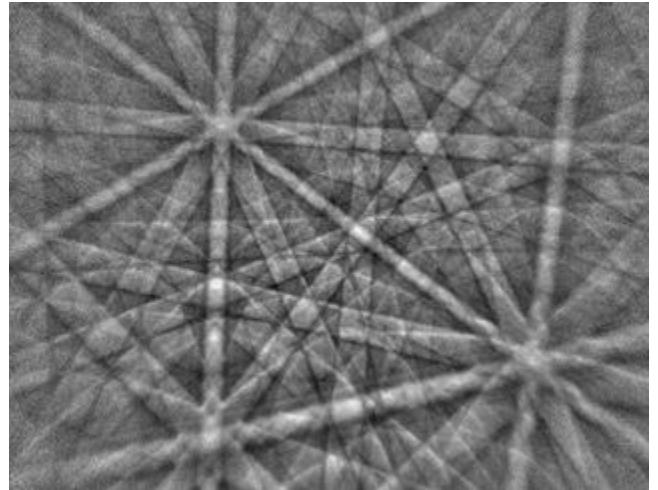


$$KAM_i = \frac{1}{K} \sum_{j=1}^K \Delta\theta_{ij}, \Delta\theta_{ij} < \Delta\theta_{lim}$$

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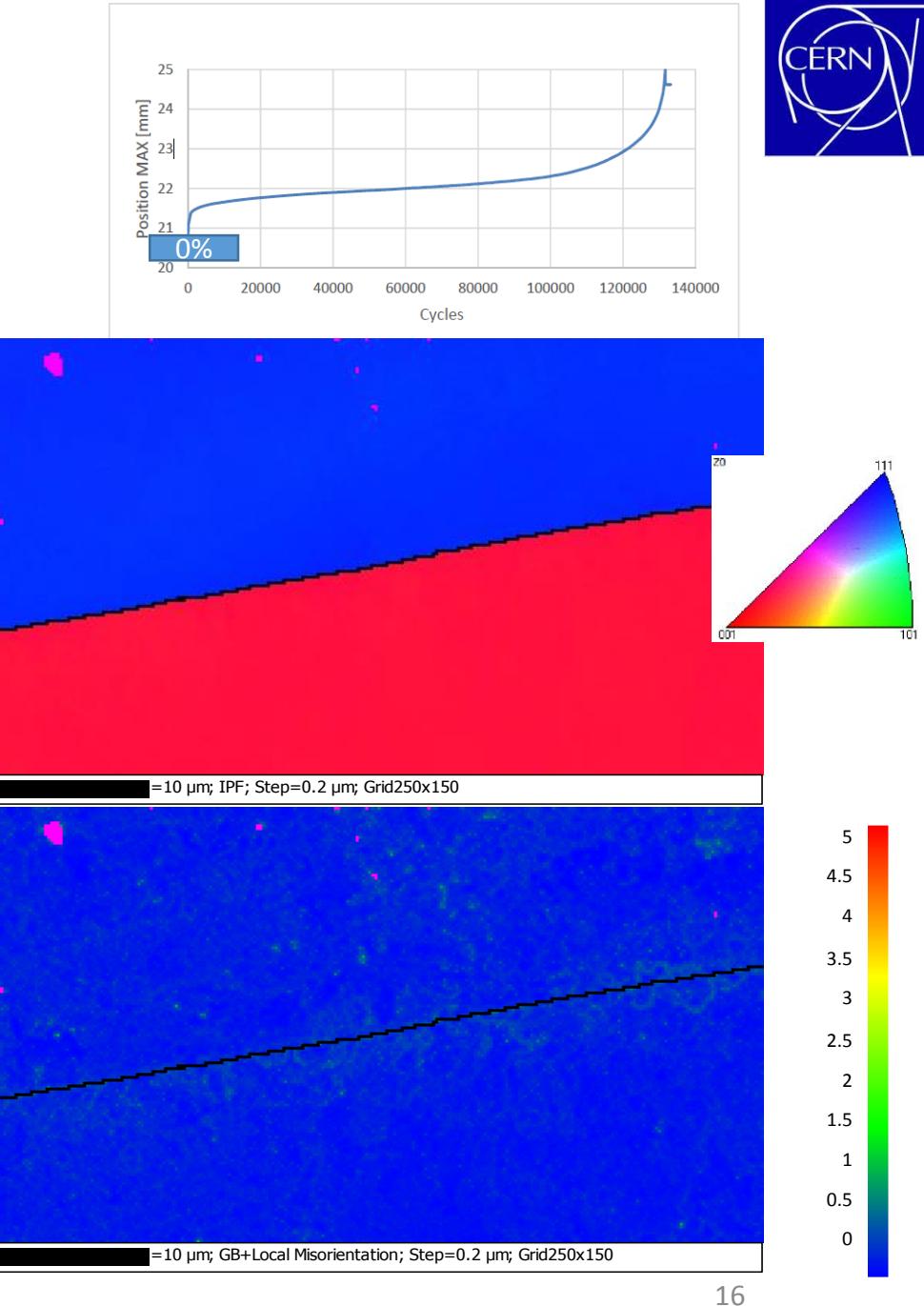
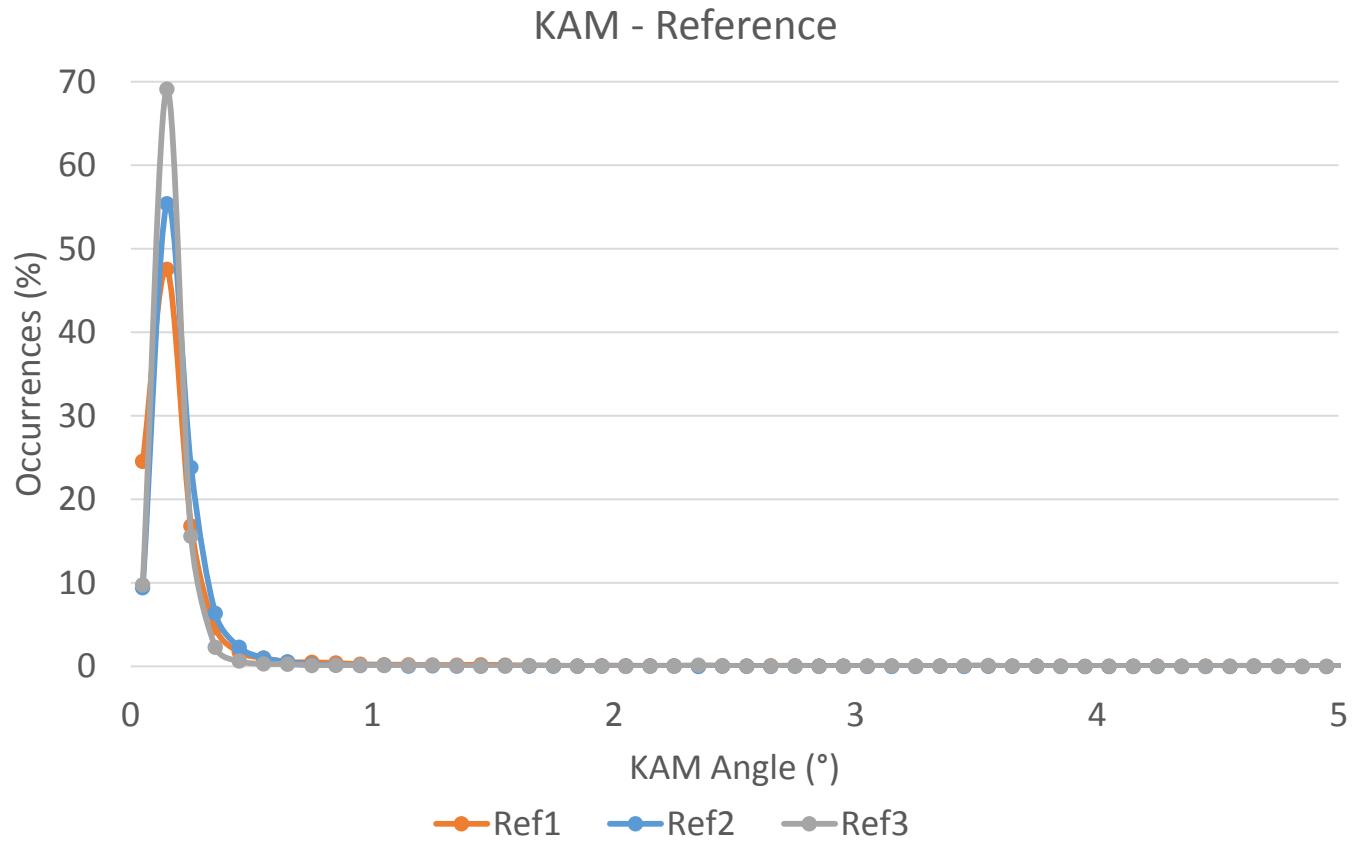
# Tensile

- It was found that tensile sample are not suitable for our analysis
  - High strain → deformation of Kikuchi bands → difficult to index



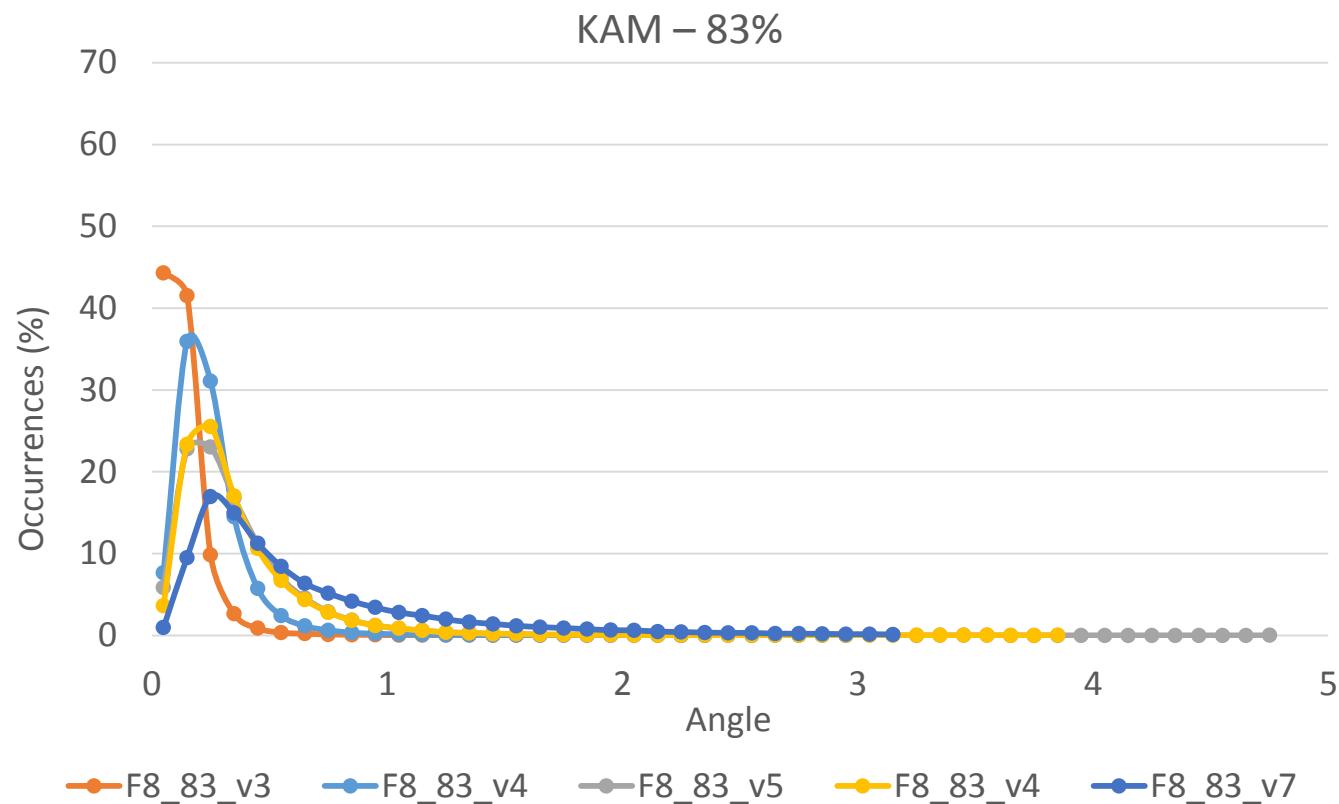
# Fatigue - Reference (0% LT)

- Narrow distribution
- Low KAM values



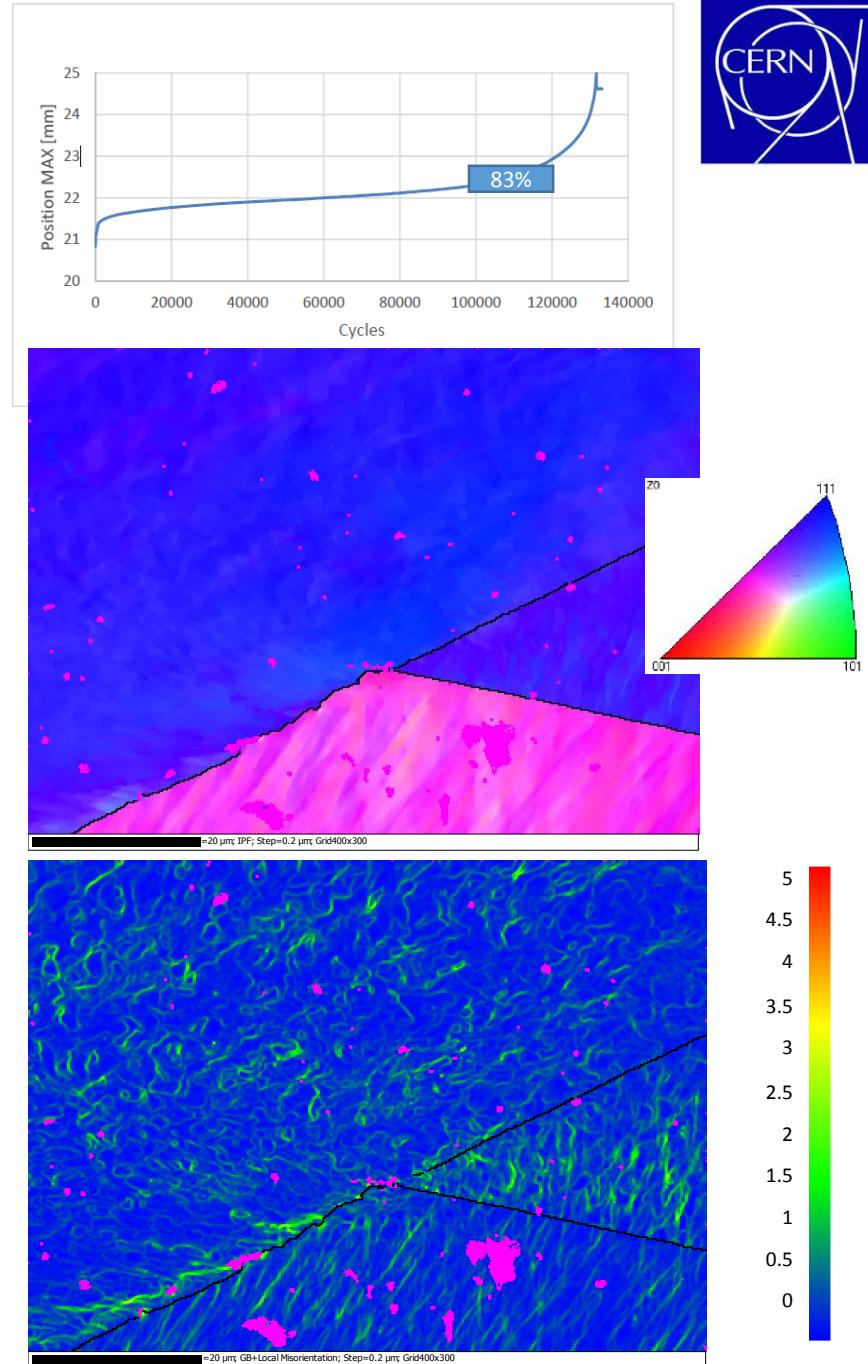
# Fatigued (83% LT)

- Broadening of the distribution
- Shift to higher value
- Higher dispersion



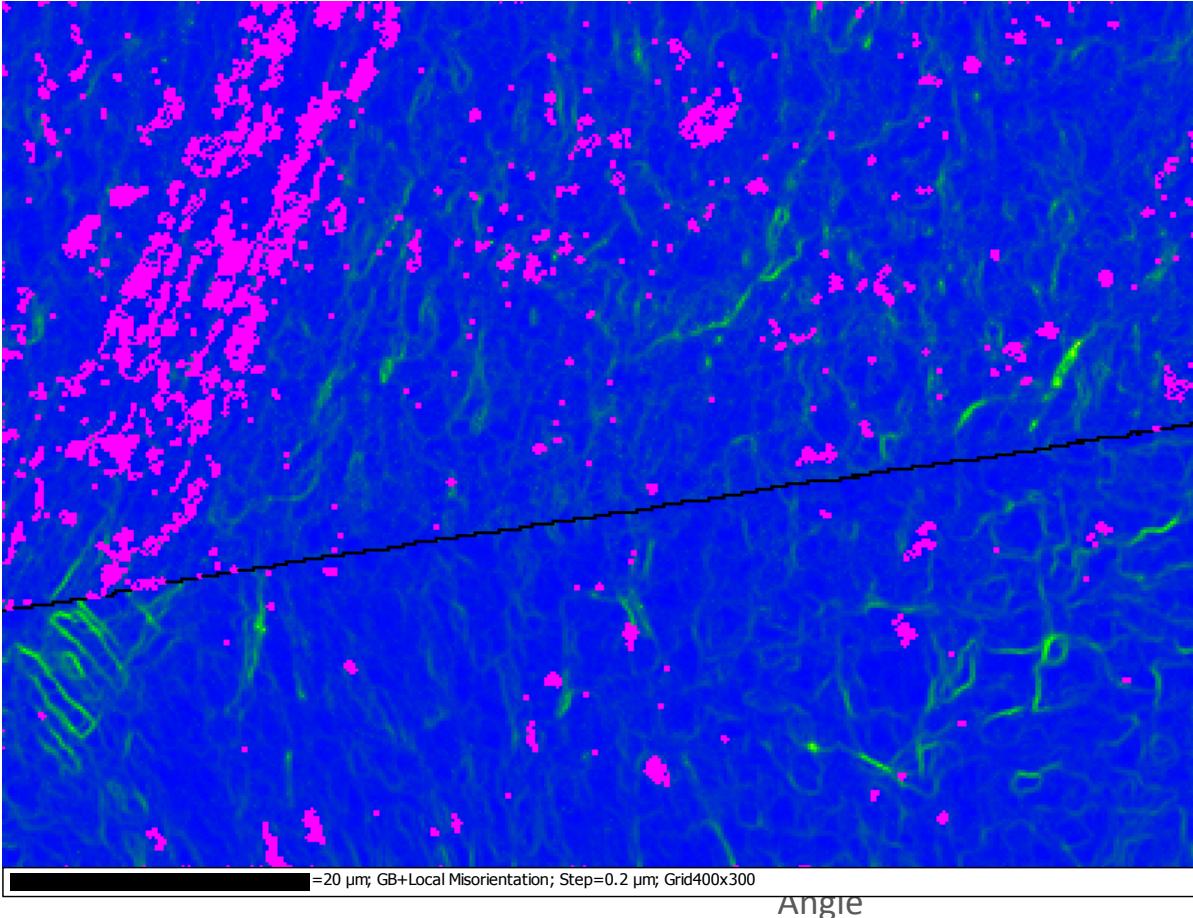
22/03/2017

Enrique Rodriguez Castro

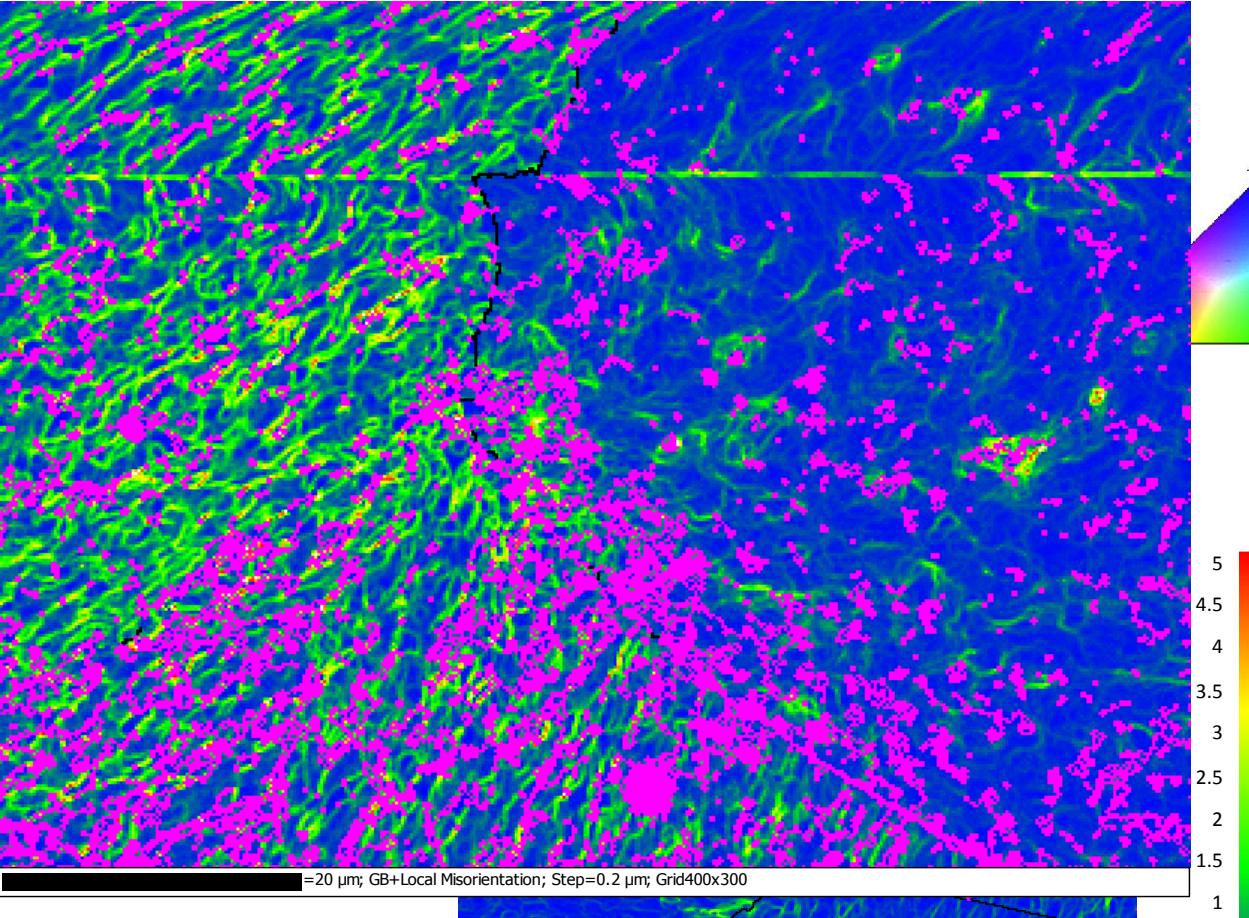


# Fatigued (83% LT)

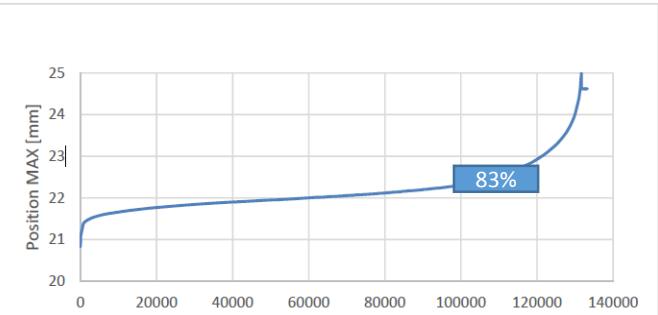
- Broadening of the distribution



22/03/2017

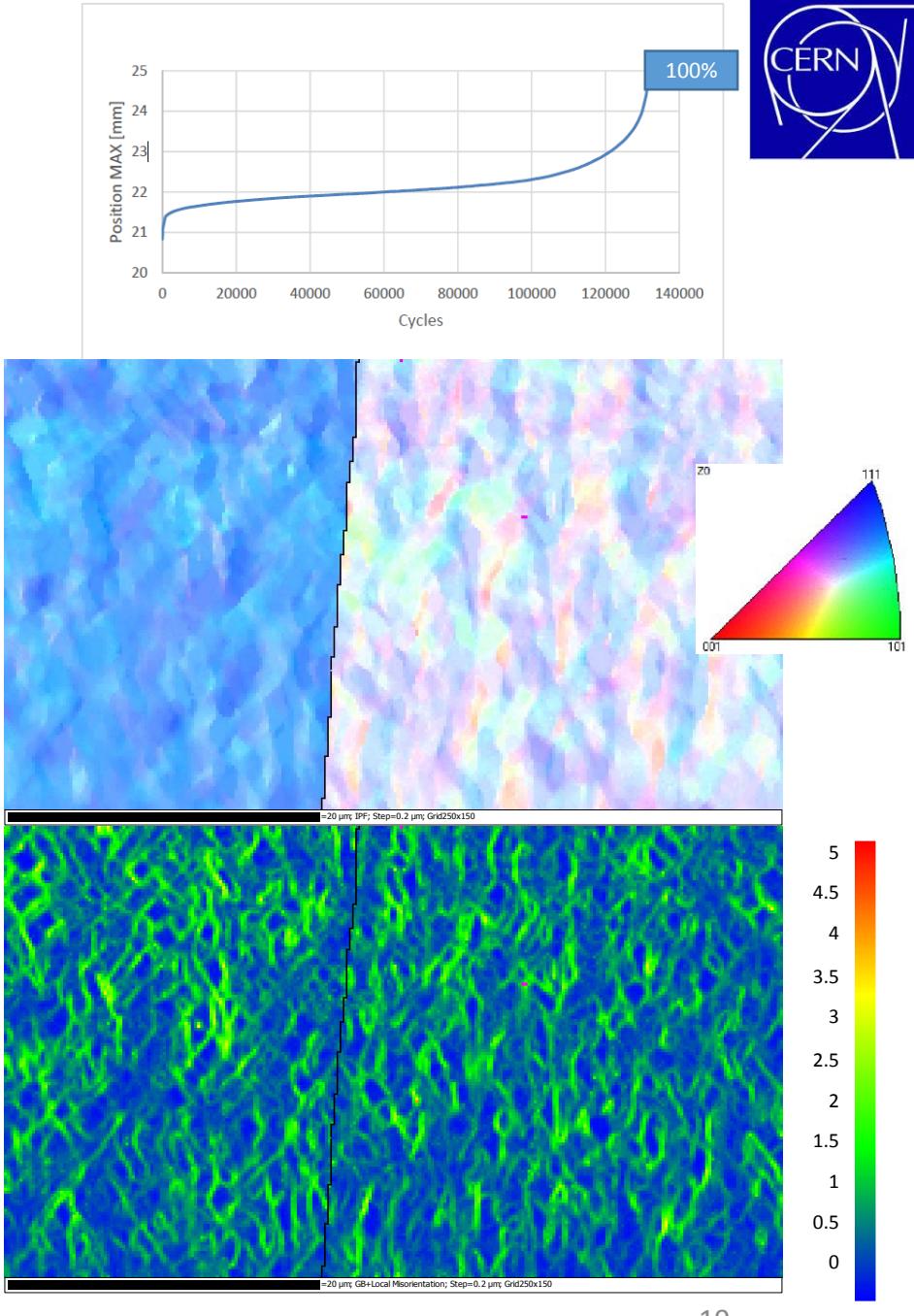
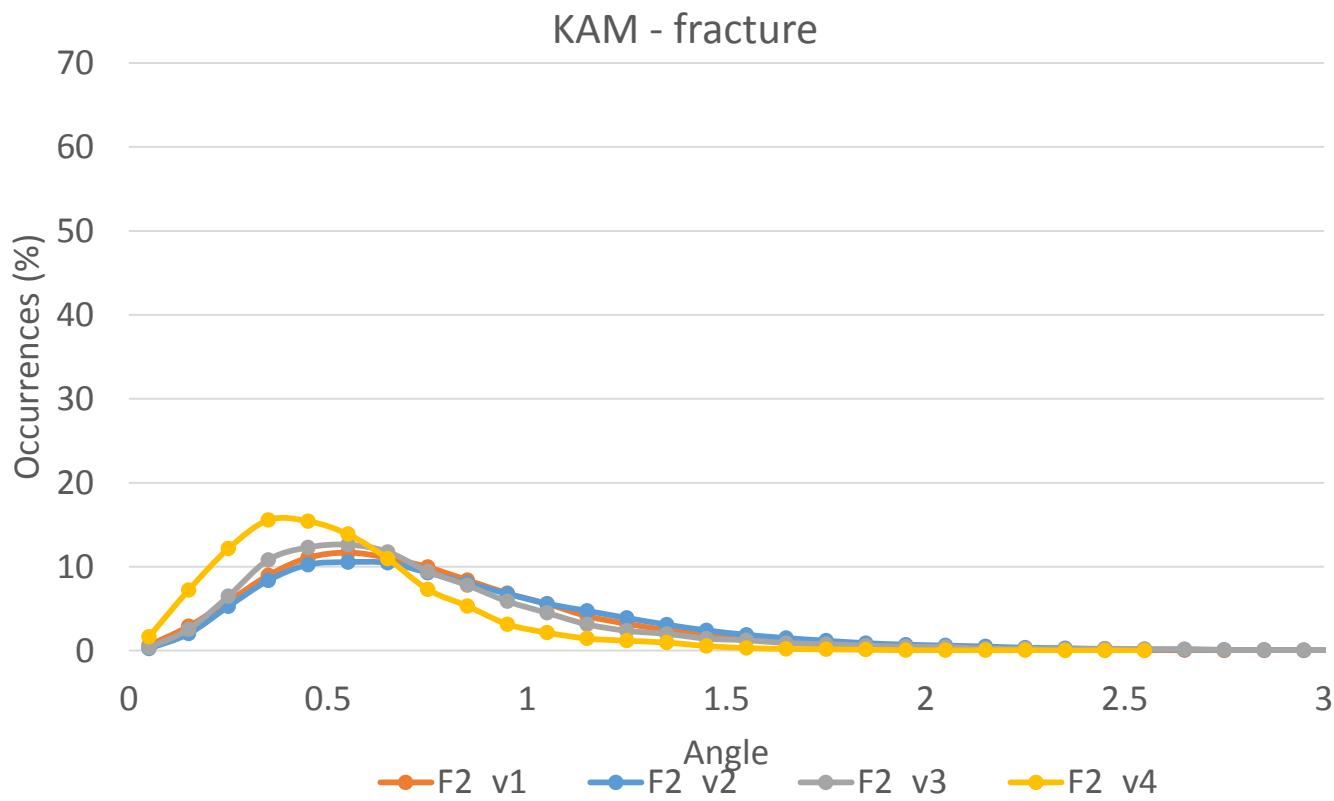


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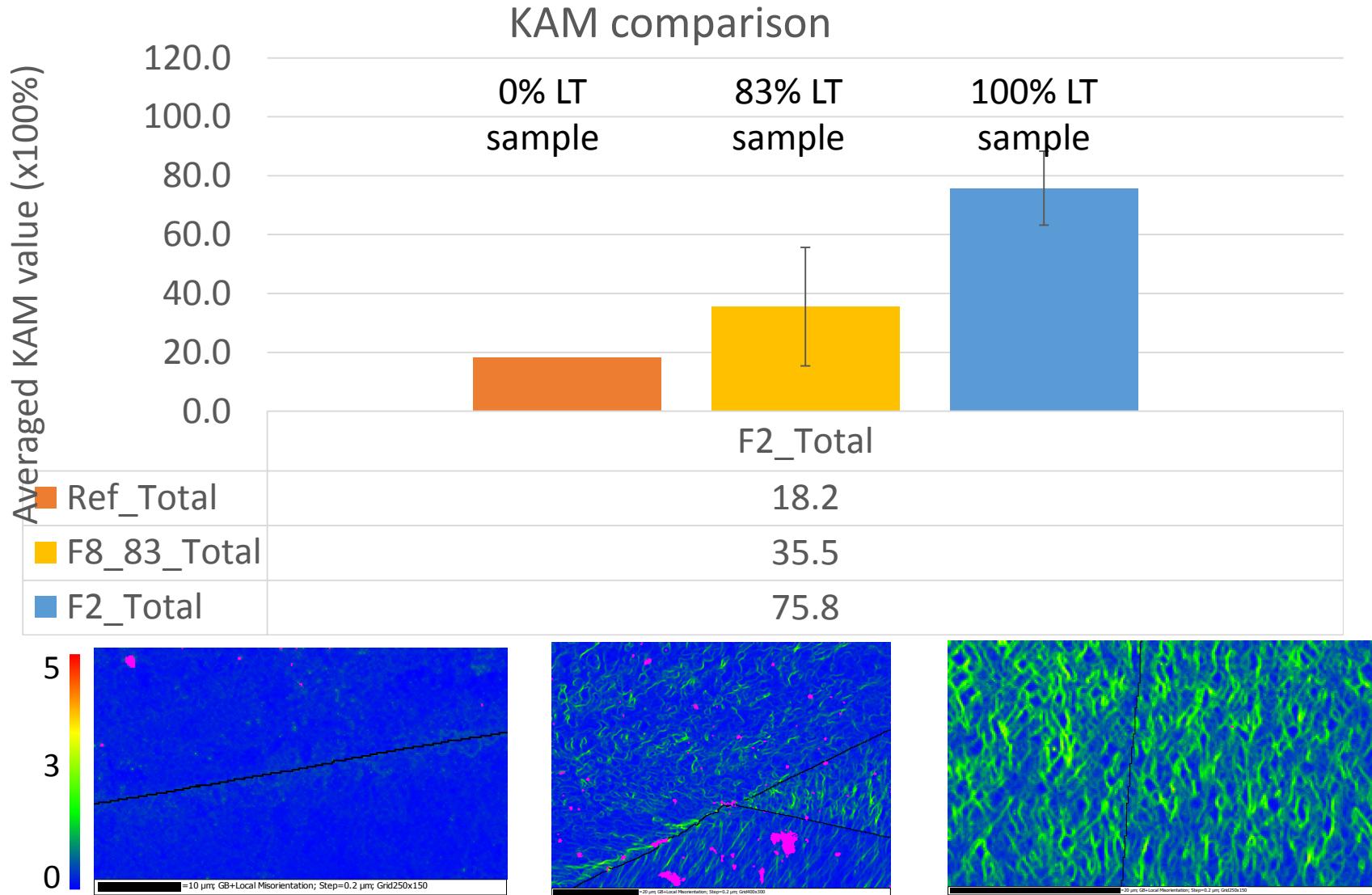


# Fatigued (100% LT)

- Strong broadening of the distribution
- Shift to even higher value

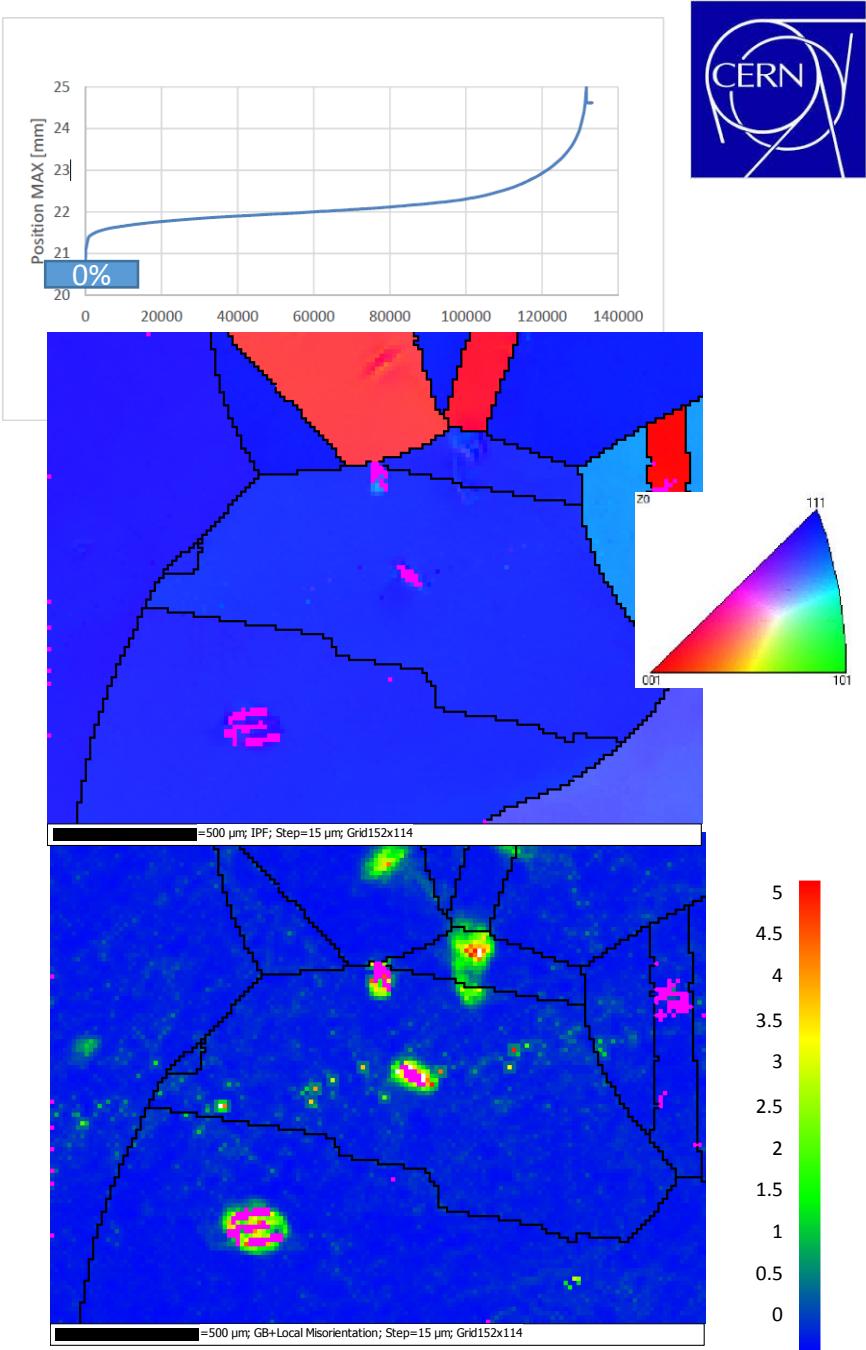
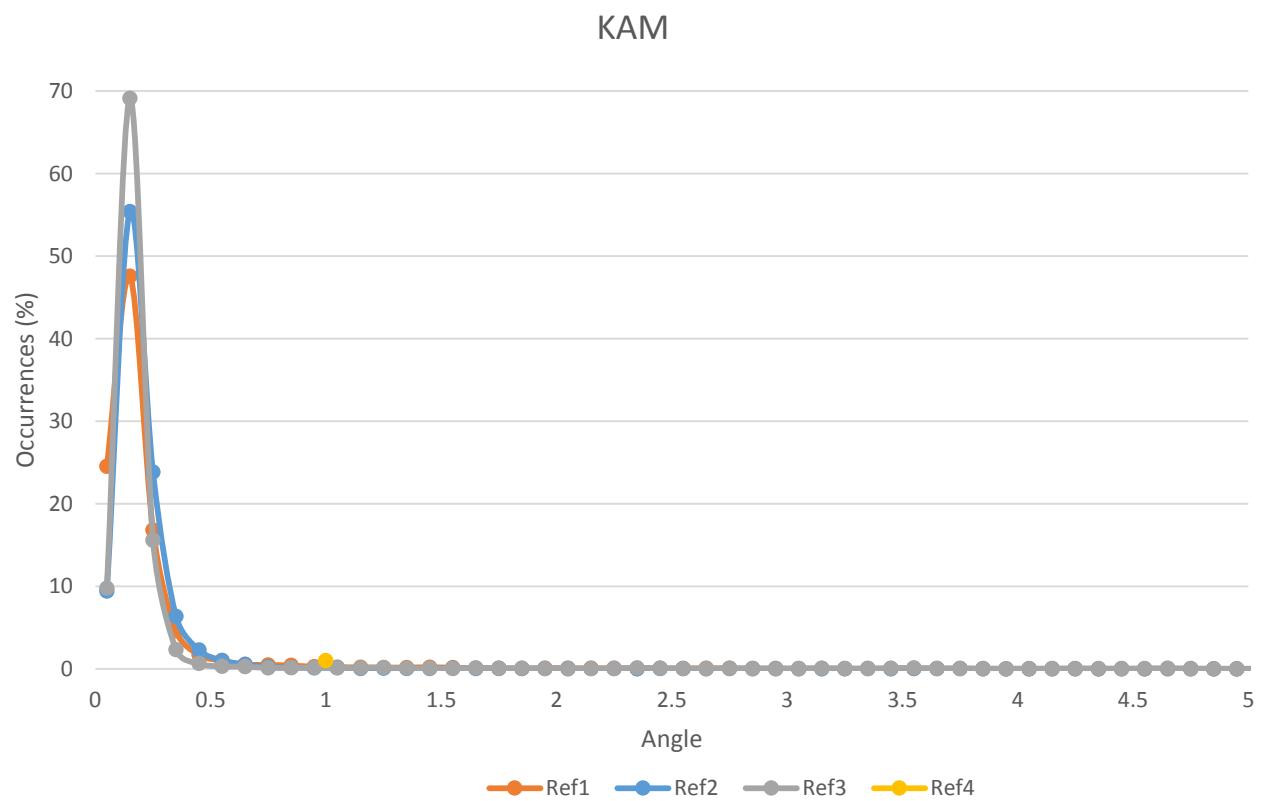


# Summary of EBSD observations



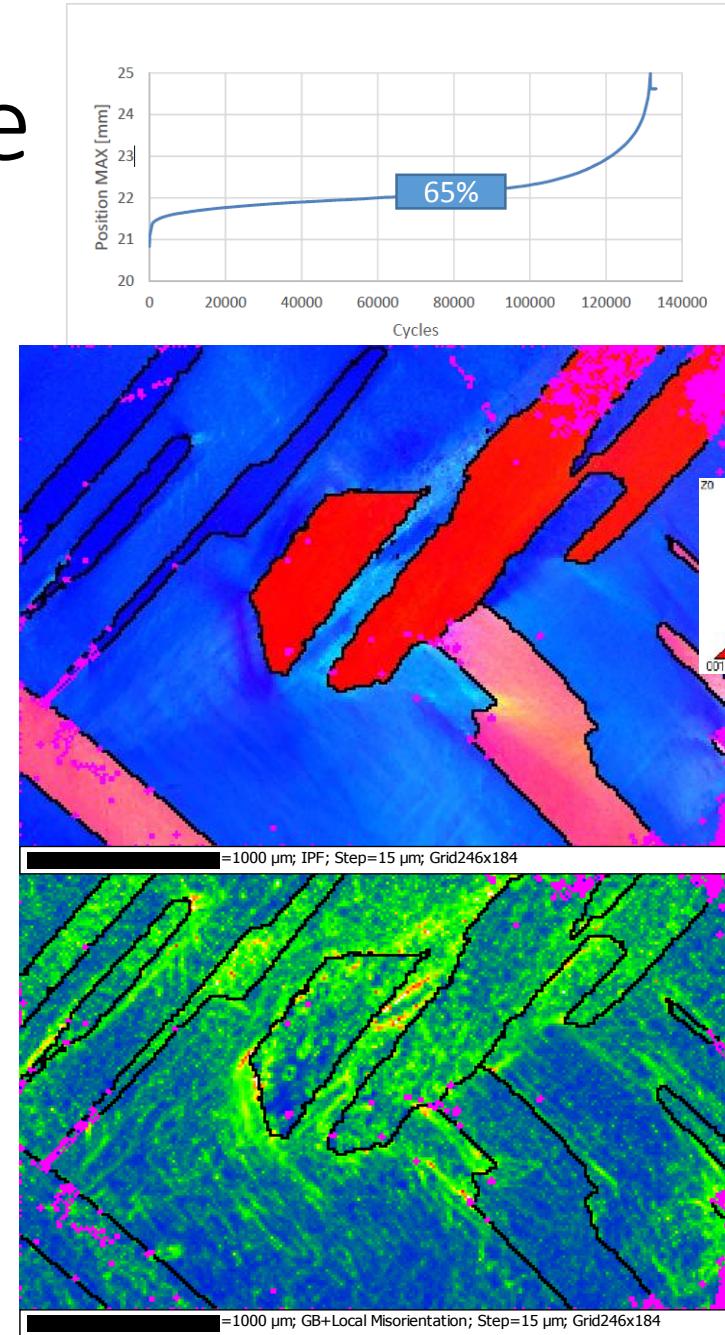
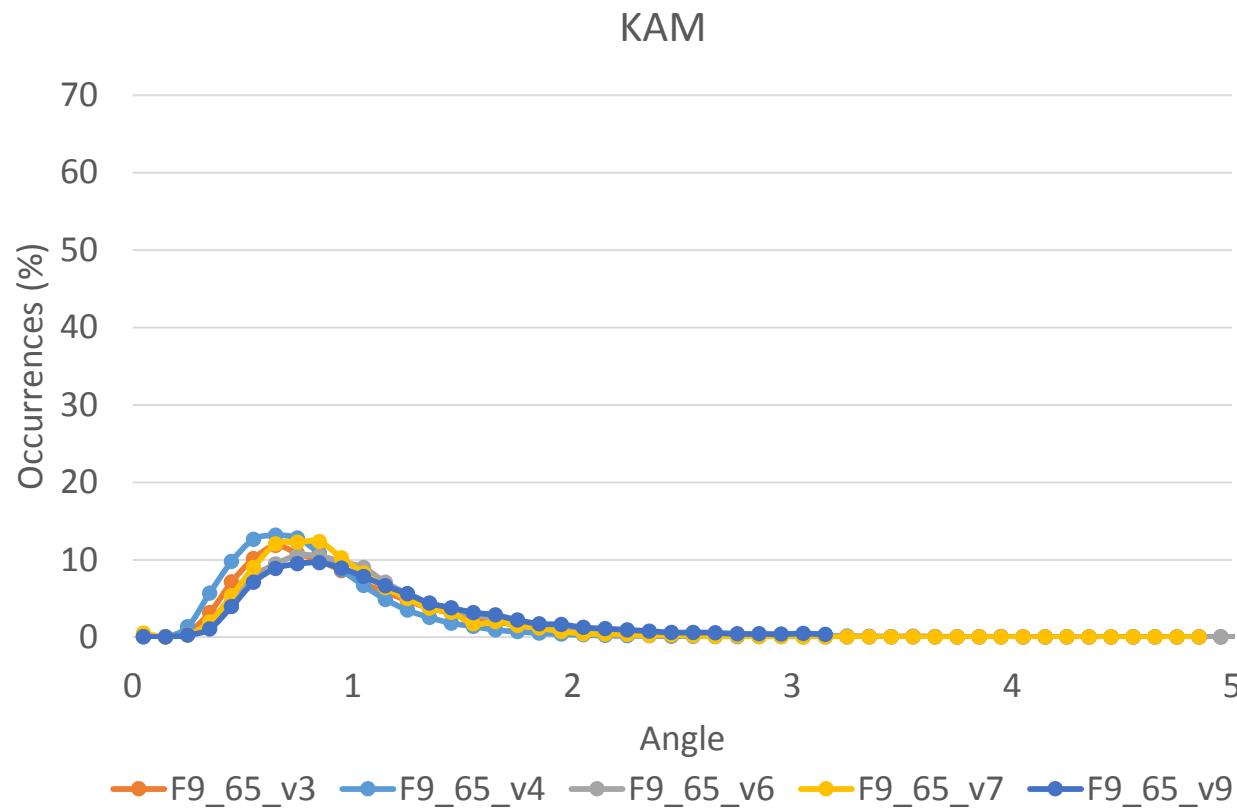
# Ref (0% LT) Stepsize = 15 $\mu\text{m}$

- Not comparable with previous due higher step size

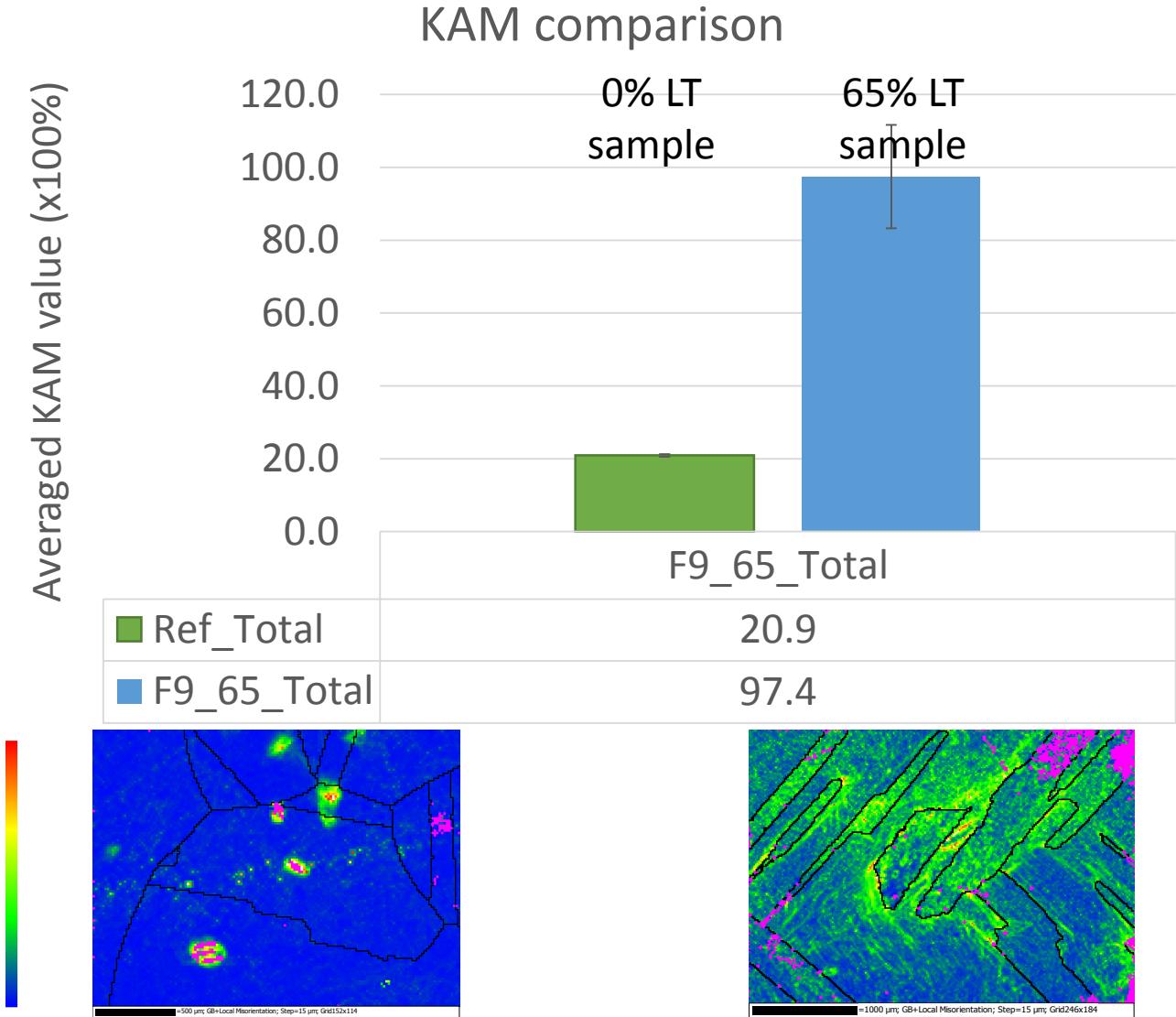


# Fatigue (65% LT) 15 $\mu\text{m}$ stepsize

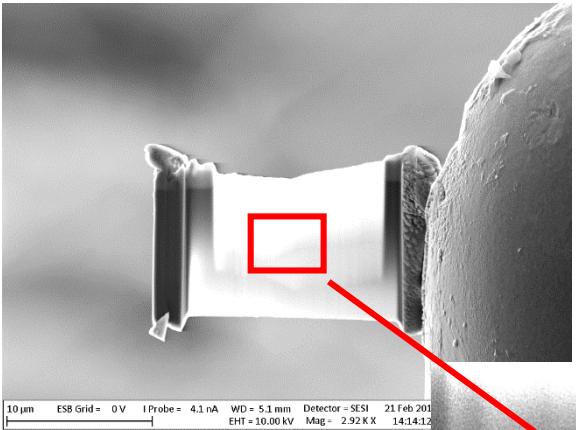
- Strong broadening of the distribution



# Comparison 15 $\mu\text{m}$ stepsize

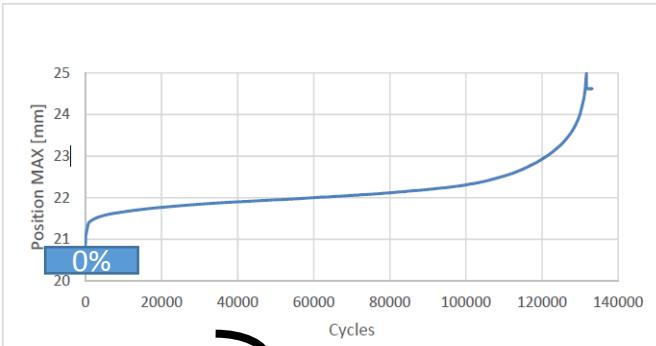
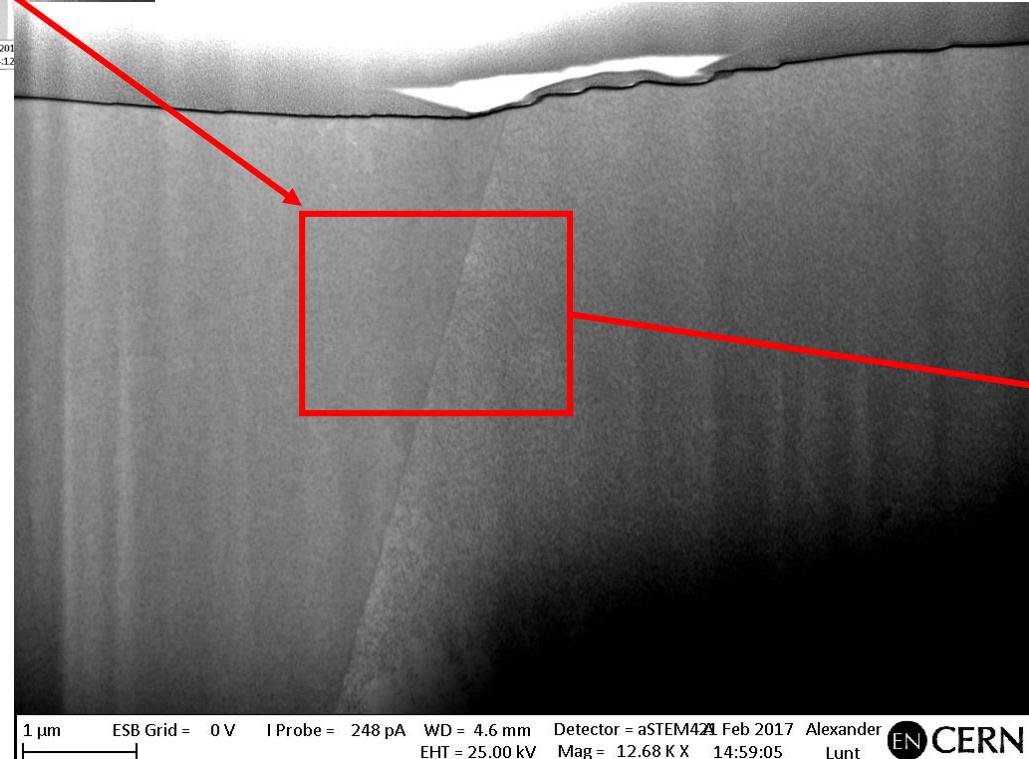


# Reference (STEM)

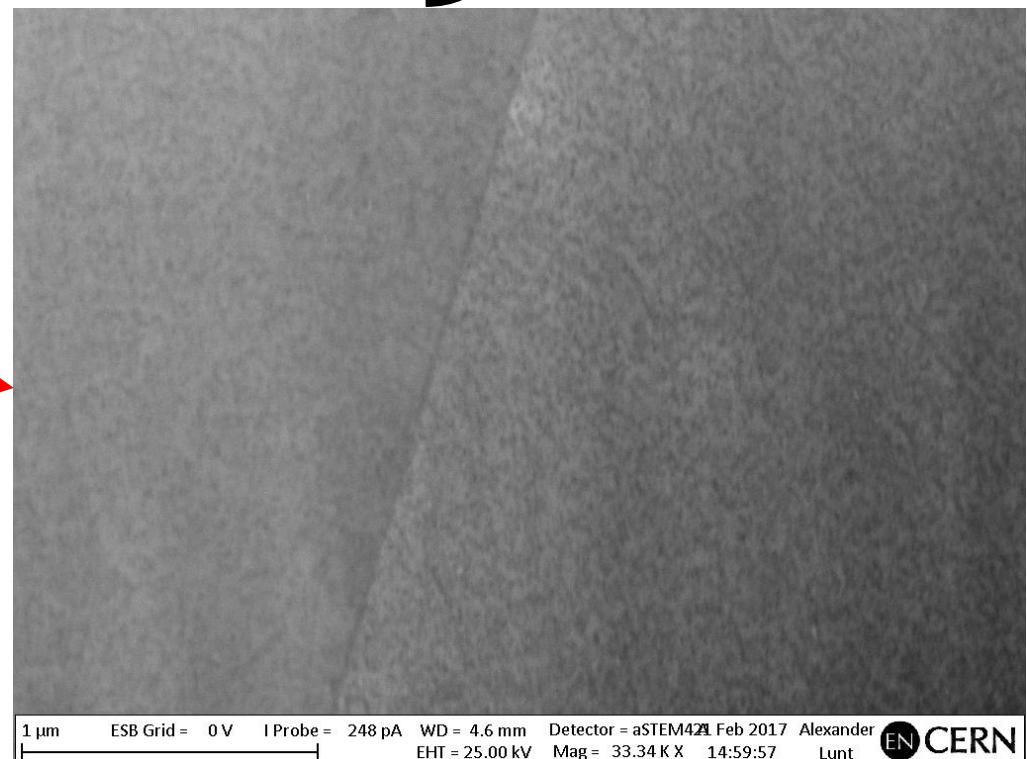


- Grain with different orientation

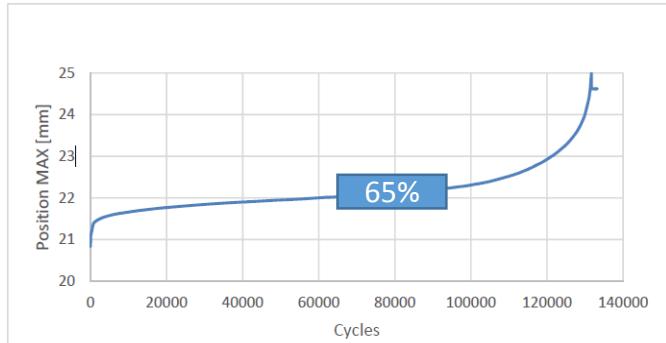
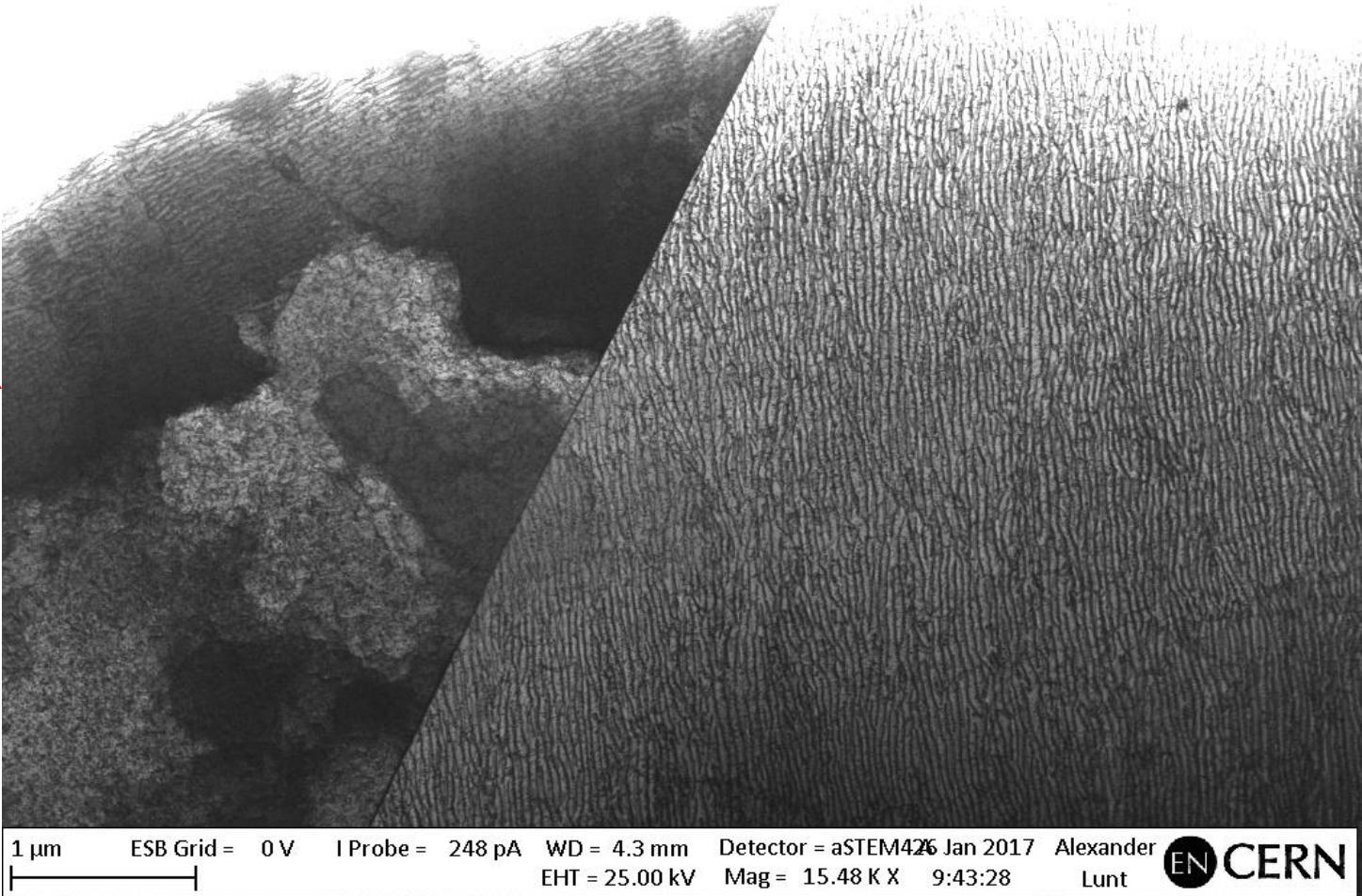
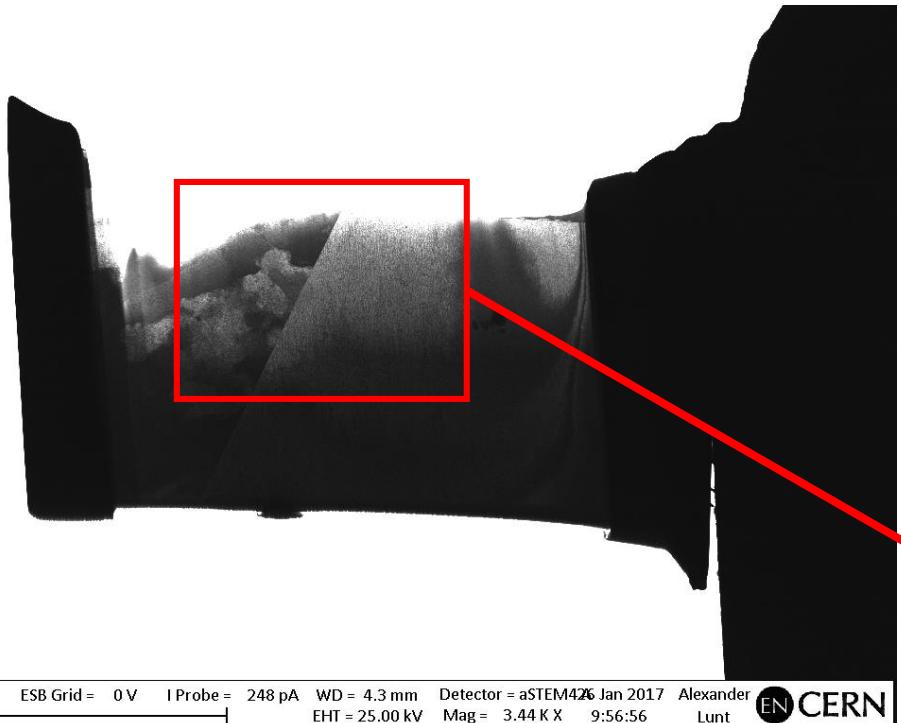
- Homogeneous
- Individual Dislocations?
- Damage effect due to Ga beam preparation



To be confirmed  
by TEM

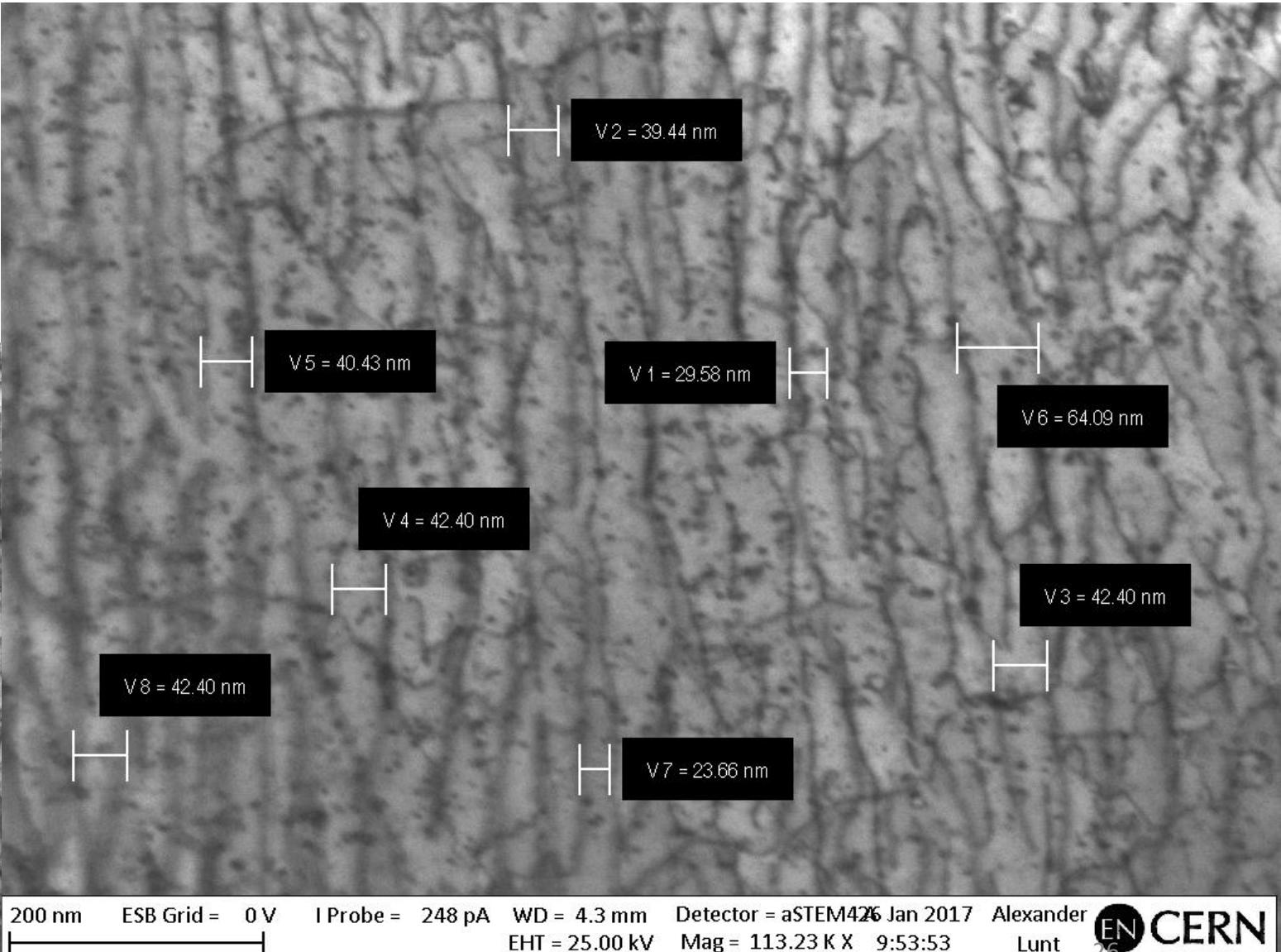
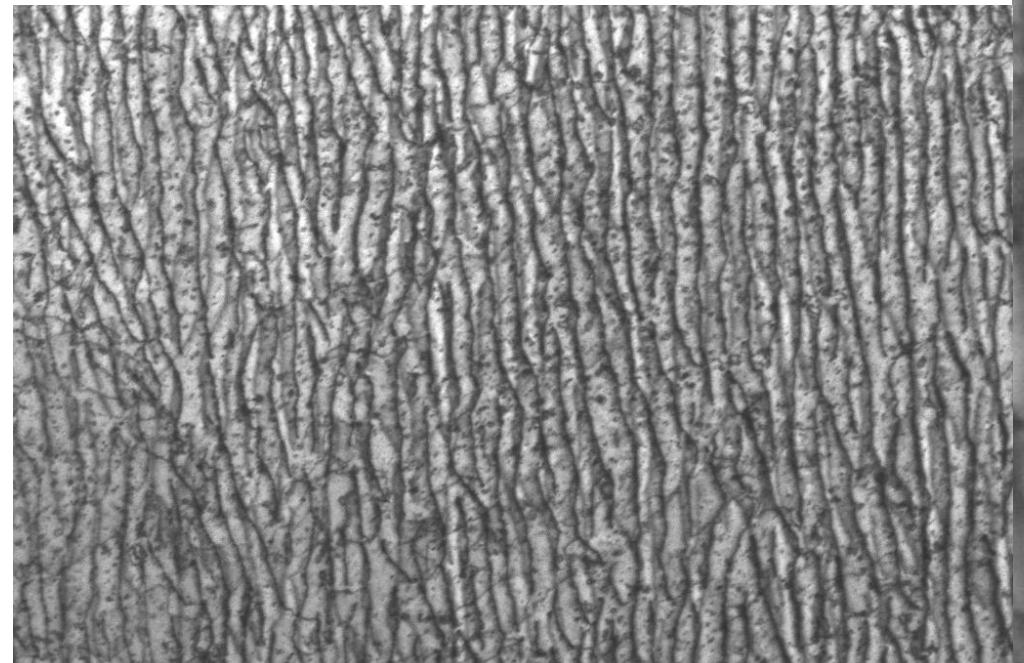


# Fatigue (65% LT) 15 $\mu$ m stepsize



# Fatigue (65% LT) 15μm stepsize

- Well structured in ladder type
- 20 – 60 nm

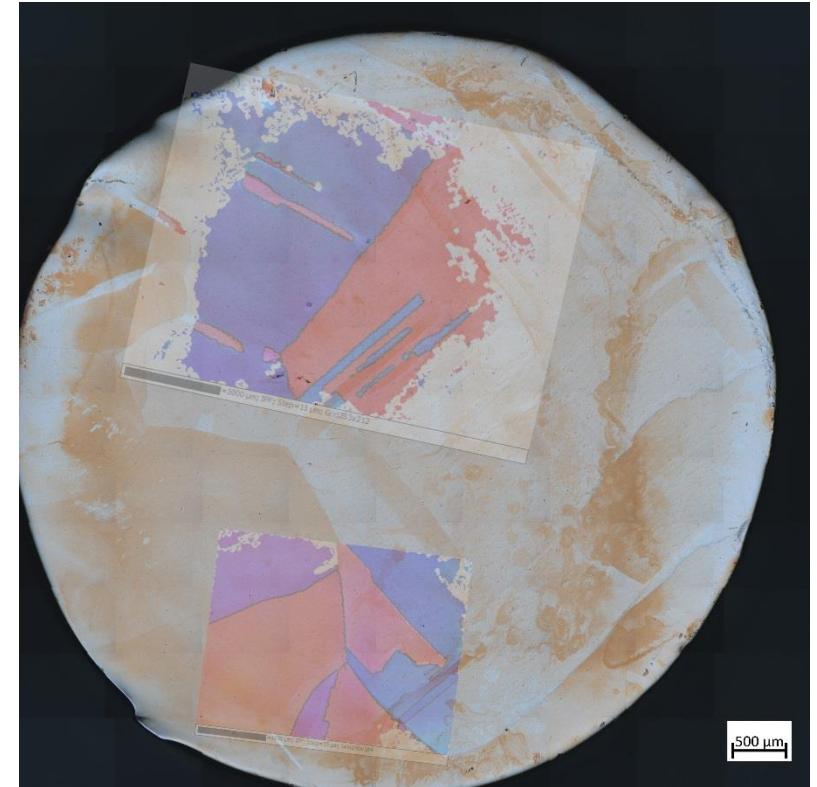
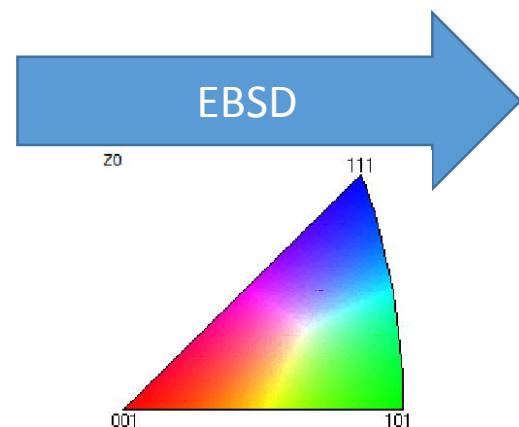


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# Perspectives

- Those maps are important to select the area where the lamella (with SEM-FIB microscope) will be taken



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# Conclusions

- EBSD has proved:
  - To be a good technique for quantification of ***dislocations arrangements over a large area.***
  - Different samples studied sample have higher dislocation density for increasing stress levels.
  - Statistics to be improved (currently only 3 stress levels and 2 lamellas)
- Further analysis with TEM
  - To confirm the observation done with STEM
  - To validate if observation of ***dislocations patterns*** through KAM maps (local mis-orientations) is possible → arrangement of dislocation patterns in bigger structures

# Thank you for your attention

Questions?

100 µm



EHT = 20.00 kV  
WD = 10.0 mm  
Signal A = SE2

Sample ID = G02-1\_

Stage at T = 0.0 °

Enrique Rodriguez Castro  
Date : 7 Nov 2016  
Mag = 200 X





# Dislocation patterns in Cu-OFE by EBSD and their relation with BD

Advanced studies

Enrique RODRIGUEZ CASTRO  
(CERN & University of Vigo)

# Future

- FIB
  - In a well characterized area
  - Lamella
  - STEM

